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Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Zener			
Zener			
Zener			
Duration	# Lots	# Quantity	# Rejects
N/A	see below	all parts	see below
24 hours			
3 cycles	1514	64430	0
1000 hours	\$ 250	11400	0
1000 hours	\$ 44	1920	0
d 150%C 1000		1 4000	0
	5 511	14080	0
96 hours	311	14080	0
- /			
R = 80 % of			
	311	14080	0
o insure ΔTi =			
	312	14120	0
10 s	269	8070	0
	19	6660	0
	N/A % 24 hours 168 hours 3 cycles wed reverse 1000 hours w. datasheet 1000 hours w. datasheet 1000 cycles wed 150°C 1000 cycles 96 hours 96 hours a) 1000 hours x = 80 % of 1000 hours b insure ΔTj = 1000 hours	N/Asee below $\%$ $24 \text{ hours} \\ 168 \text{ hours} \\ 3 \text{ cycles}$ 1514 $24 \text{ hours} \\ 3 \text{ cycles}$ 1514 250 1000 hours 250 44 1000 hours 44 24 150°C 1000 cycles 311 26 hours 311 $3)$ 311 $2 = 80 \% \text{ of}$ 1000 hours 311 $2 \text{ insure } \Delta \text{Tj} =$ 1000 hours 312 10 s 269	N/A see below all parts $\frac{9}{168}$ $\frac{24}{168}$ hours $\frac{1514}{64430}$ $\frac{1000}{100}$ hours $\frac{1514}{1400}$ $\frac{64430}{1400}$ $\frac{1000}{100}$ hours $\frac{250}{11400}$ $\frac{11400}{1400}$ $\frac{1000}{100}$ hours $\frac{44}{1920}$ $\frac{1920}{1400}$ $\frac{96}{1000}$ hours $\frac{311}{14080}$ $\frac{14080}{1400}$ a) $\frac{1000}{1000}$ hours $\frac{311}{14080}$ $\frac{14080}{1400}$ a = 80% of 1000 hours $\frac{311}{14080}$ $\frac{14120}{100}$ $10 s$ 269 8070 $\frac{10}{100}$ $\frac{10}{100}$

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

(FIT) MTTF (hrs)
2,68E+09

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